

# Improving the Reliability of the Multiline TRL Calibration Algorithm

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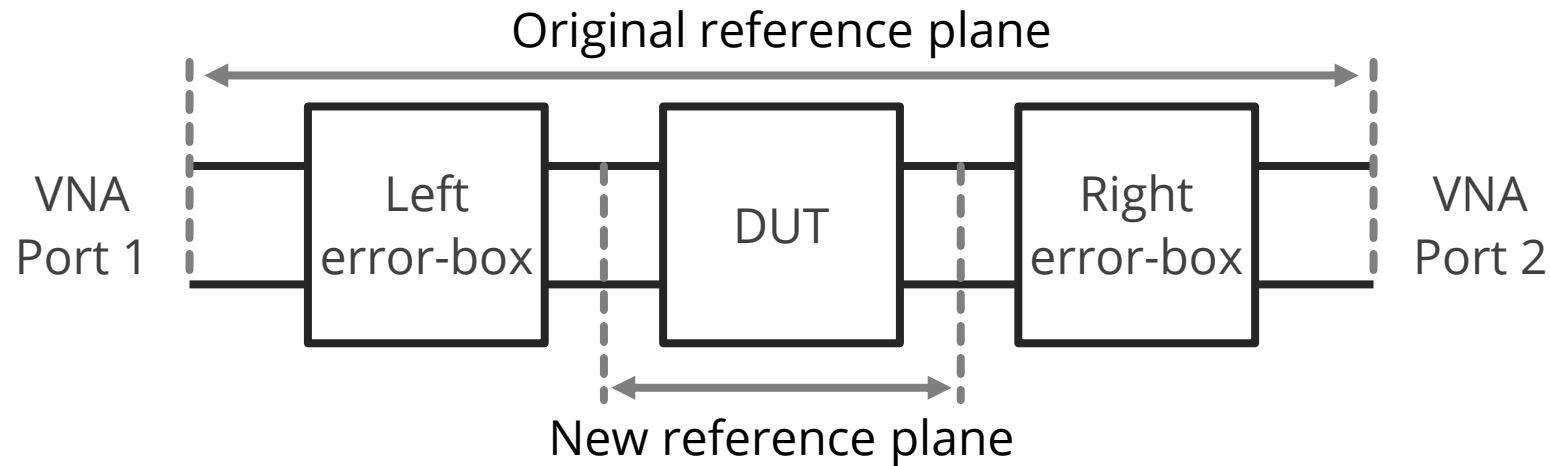
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**TONI**



# VNA Error-box Model



- Measurement is modeled using the cascade-parameters (T-parameters):

$$\mathbf{M}_{DUT} = \underbrace{k_a \begin{bmatrix} a_{11} & a_{12} \\ a_{21} & 1 \end{bmatrix}}_{\text{left error-box}} \mathbf{T}_{DUT} \underbrace{\begin{bmatrix} b_{11} & b_{12} \\ b_{21} & 1 \end{bmatrix} k_b}_{\text{right error-box}}$$

- Combine  $k_a$  and  $k_b$  to form the 7-term model (6 in  $\mathbf{A}$  and  $\mathbf{B}$ , and  $k$  is the 7<sup>th</sup>):

$$\mathbf{M}_{DUT} = k \mathbf{A} \mathbf{T}_{DUT} \mathbf{B}$$

# Thru-Reflect-Line (TRL) Calibration

- **Thru** standard, fully known:

$$\mathbf{M}_{Thru} = k\mathbf{A} \begin{bmatrix} 1 & 0 \\ 0 & 1 \end{bmatrix} \mathbf{B}$$

- **Line** standard, only length known:

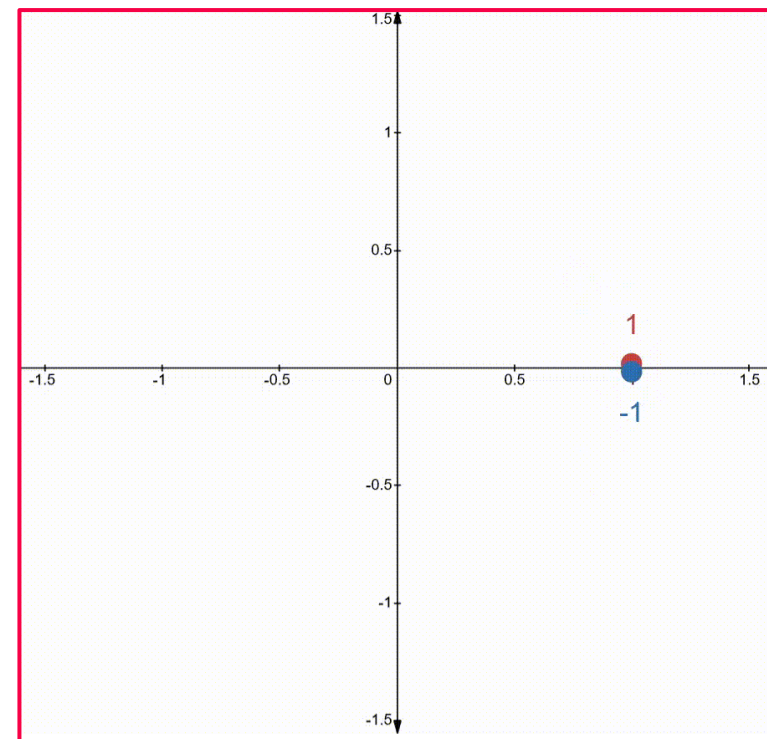
$$\mathbf{M}_{Line} = k\mathbf{A} \begin{bmatrix} e^{-\gamma l} & 0 \\ 0 & e^{\gamma l} \end{bmatrix} \mathbf{B}$$

- The **eigenvalue** problem:

$$\mathbf{M}_{Line}\mathbf{M}_{Thru}^{-1} = \mathbf{A} \begin{bmatrix} e^{-\gamma l} & 0 \\ 0 & e^{\gamma l} \end{bmatrix} \mathbf{A}^{-1}$$

When  $e^{-\gamma l} = e^{\gamma l}$ , the calibration becomes **unsolvable**.

- **Reflect** standard, unknown, but symmetric. Used with the **Thru** standard to finalize the calibration.



# Extending TRL to Multiline TRL

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- Use  $N > 2$  lines. Results in  $\frac{N(N-1)}{2}$  pairs:

$$\mathbf{M}_i \mathbf{M}_j^{-1} = \mathbf{A} \begin{bmatrix} e^{-\gamma(l_i - l_j)} & 0 \\ 0 & e^{\gamma(l_i - l_j)} \end{bmatrix} \mathbf{A}^{-1}$$

- **Question:** How to combine the solutions (eigenvectors) of all pairs?

- **Idea:** [R. B. Marks, MTT, 39, (1991)]

Combine the eigenvectors using the Gauss-Markov theorem (weighted sum).

- Constraints:
  - 1) Error propagation through the eigenvectors (error-boxes) are assumed linear.
  - 2) Only  $N - 1$  pairs allowed to be used, where one line is common among all pairs.
    - allows for an invertible covariance matrix for the Gauss-Markov theorem.

# Can we do better?

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## Questions:

Should we enforce linearization?

Must we use Gauss-Markov method to get the best results?

To overcome this, we need to **re-develop** multiline TRL.

# Kronecker Product “ $\otimes$ ” and Matrix Vectorization

- Given matrices  $\mathbf{X}$  and  $\mathbf{Y}$ , their Kronecker Product is defined as:

$$\mathbf{X} \otimes \mathbf{Y} = \begin{bmatrix} x_{11}\mathbf{Y} & x_{12}\mathbf{Y} & \dots \\ x_{21}\mathbf{Y} & x_{22}\mathbf{Y} & \dots \\ \vdots & \vdots & \ddots \end{bmatrix}$$

- Vectorization of a matrix  $\mathbf{X}$  is defined by stacking its columns:

$$\mathbf{X} = \begin{bmatrix} x_{11} & x_{12} \\ x_{21} & x_{22} \end{bmatrix} \xrightarrow{\text{vec}(\cdot)} \text{vec}(\mathbf{X}) = \begin{bmatrix} x_{11} \\ x_{21} \\ x_{12} \\ x_{22} \end{bmatrix}$$

- Vectorization of matrix product:** given  $\mathbf{X}$ ,  $\mathbf{Y}$  and  $\mathbf{Z}$ , then:

$$\text{vec}(\mathbf{XYZ}) = (\mathbf{Z}^T \otimes \mathbf{X})\text{vec}(\mathbf{Y})$$

# Reformulating mTRL Error-box Model (1/2)

- Measurement of  $i$ -th line standard:

$$\mathbf{M}_i = k\mathbf{A}\mathbf{L}_i\mathbf{B}$$

- Vectorization of  $\mathbf{M}_i$ :

$$\text{vec}(\mathbf{M}_i) = k(\mathbf{B}^T \otimes \mathbf{A})\text{vec}(\mathbf{L}_i)$$

- Including all  $N$  lines:

$$\underbrace{[\text{vec}(\mathbf{M}_1) \quad \cdots \quad \text{vec}(\mathbf{M}_N)]}_{\mathbf{M}} = k(\mathbf{B}^T \otimes \mathbf{A}) \underbrace{[\text{vec}(\mathbf{L}_1) \quad \cdots \quad \text{vec}(\mathbf{L}_N)]}_{\mathbf{L}}$$

$$\mathbf{M} = k(\mathbf{B}^T \otimes \mathbf{A})\mathbf{L}$$

$4 \times N$        $4 \times 4$        $4 \times N$

Eq. 1

# Reformulating mTRL Error-box Model (2/2)

- Inverse measurement of  $i$ -th line standard:

$$\mathbf{M}_i^{-1} = \frac{1}{k} \mathbf{B}^{-1} \mathbf{L}_i^{-1} \mathbf{A}^{-1}$$

- Vectorization of  $\mathbf{M}_i^{-1}$ :

$$\text{vec}(\mathbf{M}_i^{-1}) = \frac{1}{k} (\mathbf{A}^{-T} \otimes \mathbf{B}^{-1}) \text{vec}(\mathbf{L}_i^{-1})$$

- Including all  $N$  lines, and applying **some tricks** (see our paper!):

$$\underbrace{\mathbf{D}^{-1} \mathbf{M}^T \mathbf{P} \mathbf{Q}}_{N \times 4} = \frac{1}{k} \underbrace{\mathbf{L}^T \mathbf{P} \mathbf{Q}}_{N \times 4} \underbrace{(\mathbf{B}^T \otimes \mathbf{A})^{-1}}_{4 \times 4}$$

Eq. 2

$$\mathbf{P} = \begin{bmatrix} 1 & 0 & 0 & 0 \\ 0 & 0 & 1 & 0 \\ 0 & 1 & 0 & 0 \\ 0 & 0 & 0 & 1 \end{bmatrix}; \quad \mathbf{Q} = \begin{bmatrix} 0 & 0 & 0 & 1 \\ 0 & -1 & 0 & 0 \\ 0 & 0 & -1 & 0 \\ 1 & 0 & 0 & 0 \end{bmatrix}; \quad \mathbf{D} = \text{diag}([\det(\mathbf{M}_1) \quad \dots \quad \det(\mathbf{M}_N)])$$



# Solving for the Propagation Constant $\gamma$

- Simplifying notation by letting  $X = (B^T \otimes A)$

$$\boxed{M} = \boxed{kXL} \quad \text{1}$$

$$D^{-1}M^T P Q = \frac{1}{k} L^T P Q X^{-1} \quad \text{2}$$

- Multiplying Eq. (1) to the **right** of Eq. (2):

$$\underbrace{D^{-1}M^T P Q M}_{\text{Measurement}} = \underbrace{L^T P Q L}_{\text{Line Model}}$$

- Find  $\gamma$  through optimization:

$$\gamma_{opt} = \min_{\gamma} \left\| D^{-1}M^T P Q M - L_{(\gamma)}^T P Q L_{(\gamma)} \right\|_F^2$$

# Formulating the Eigenvalue Problem (1/2)

- We multiply an  $N \times N$  matrix  $W$  to Eq. (1):

$$\begin{aligned} \boxed{MW} &= \boxed{kXLW} && \textcircled{1} \\ \swarrow & \searrow && \\ D^{-1}M^T PQ &= \frac{1}{k} L^T PQ X^{-1} && \textcircled{2} \end{aligned}$$

- Then, we multiply Eq. (1) to the **left** of Eq. (2):

$$\underbrace{MW D^{-1} M^T PQ}_F = X \underbrace{LW L^T PQ}_{H} X^{-1}$$

- We end up with a similarity equation:

$$F = X H X^{-1}$$

- If  $H$  is diagonal, then we have an eigenvalue problem.

# Formulating the Eigenvalue Problem (2/2)

- It turns out that if  $W$  is skew-symmetric, then  $H$  becomes diagonal:

$$W = \begin{bmatrix} 0 & w_{12} & w_{13} & w_{14} & \cdots \\ -w_{12} & 0 & w_{23} & w_{24} & \ddots \\ -w_{13} & -w_{23} & 0 & w_{34} & \ddots \\ -w_{14} & -w_{24} & -w_{34} & 0 & \ddots \\ \vdots & \ddots & \ddots & \ddots & \ddots \end{bmatrix} \xrightarrow{\text{yields}} H = \begin{bmatrix} -\lambda & 0 & 0 & 0 \\ 0 & 0 & 0 & 0 \\ 0 & 0 & 0 & 0 \\ 0 & 0 & 0 & \lambda \end{bmatrix}$$

$$\lambda = \sum_{\substack{i=1 \\ i < j \leq N}}^{N-1} w_{ij} \cdot \left( e^{\gamma(l_i - l_j)} - e^{-\gamma(l_i - l_j)} \right)$$

- The eigenvalue problem is only solvable if  $|\lambda| > 0$ . This is enforced if:

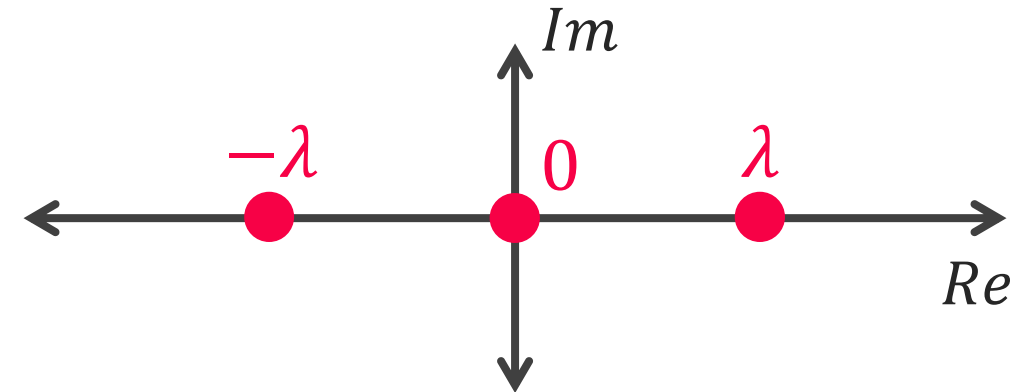
$$w_{ij} = \text{conj} \left( e^{\gamma(l_i - l_j)} - e^{-\gamma(l_i - l_j)} \right)$$

# Solving the Calibration Problem

- The eigenvalue problem:

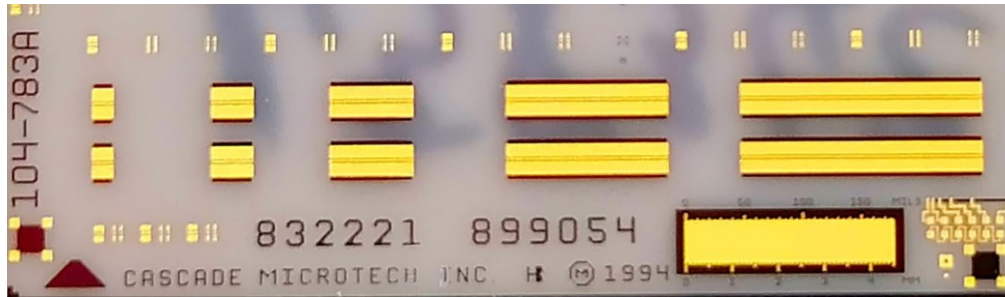
$$F = X \begin{bmatrix} -\lambda & 0 & 0 & 0 \\ 0 & 0 & 0 & 0 \\ 0 & 0 & 0 & 0 \\ 0 & 0 & 0 & \lambda \end{bmatrix} X^{-1}$$

$$\lambda = \sum_{\substack{i=1 \\ i < j \leq N}}^{N-1} \left| e^{\gamma(l_i - l_j)} - e^{-\gamma(l_i - l_j)} \right|^2$$



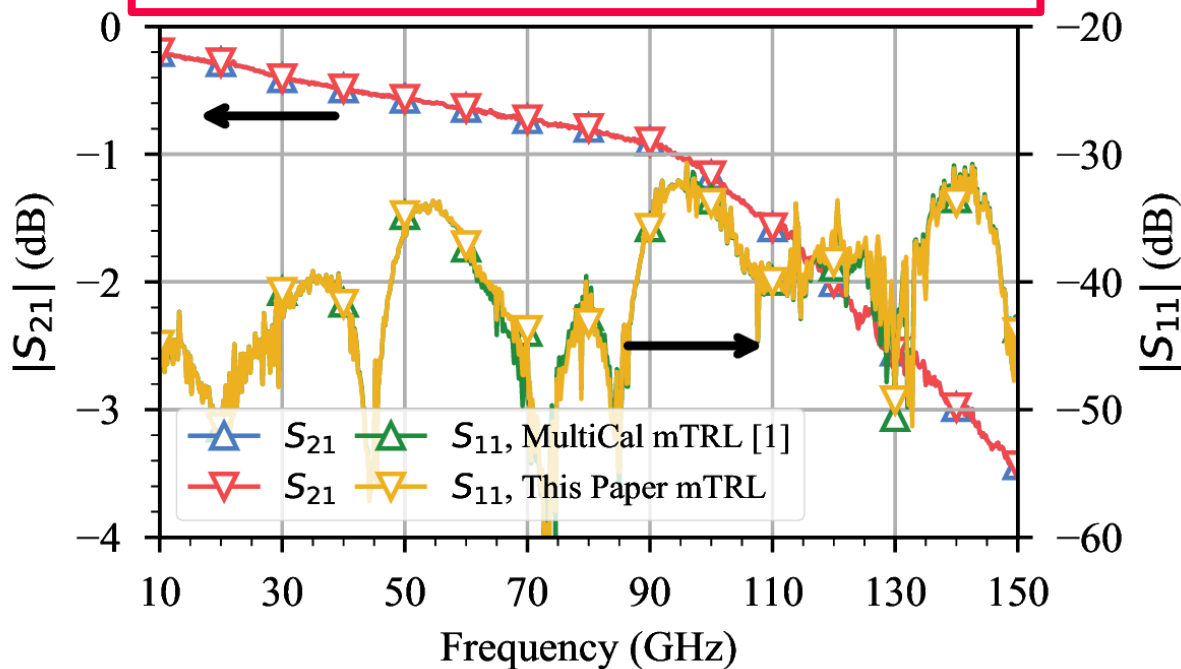
- The eigenvectors of  $F$  are the columns of  $X$  (up to a scalar factor).
- The rest of the calibration is solved using the **Reflect** and **Thru** standards.

# On-wafer Measurements

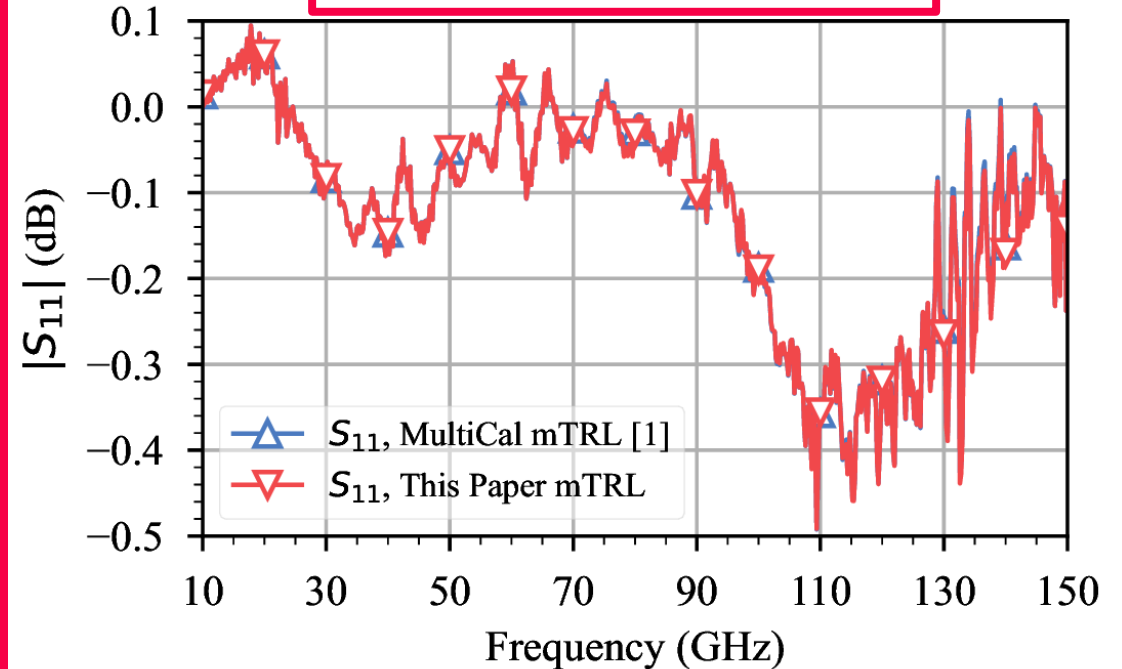


- **Calibration standards:** 4 CPWs lines {0.2, 0.45, 0.9, 1.8}mm and a Short.
- 1 CPW line 3.5mm used for verification (not part of the calibration).

Calibrated verification line: 3.5mm

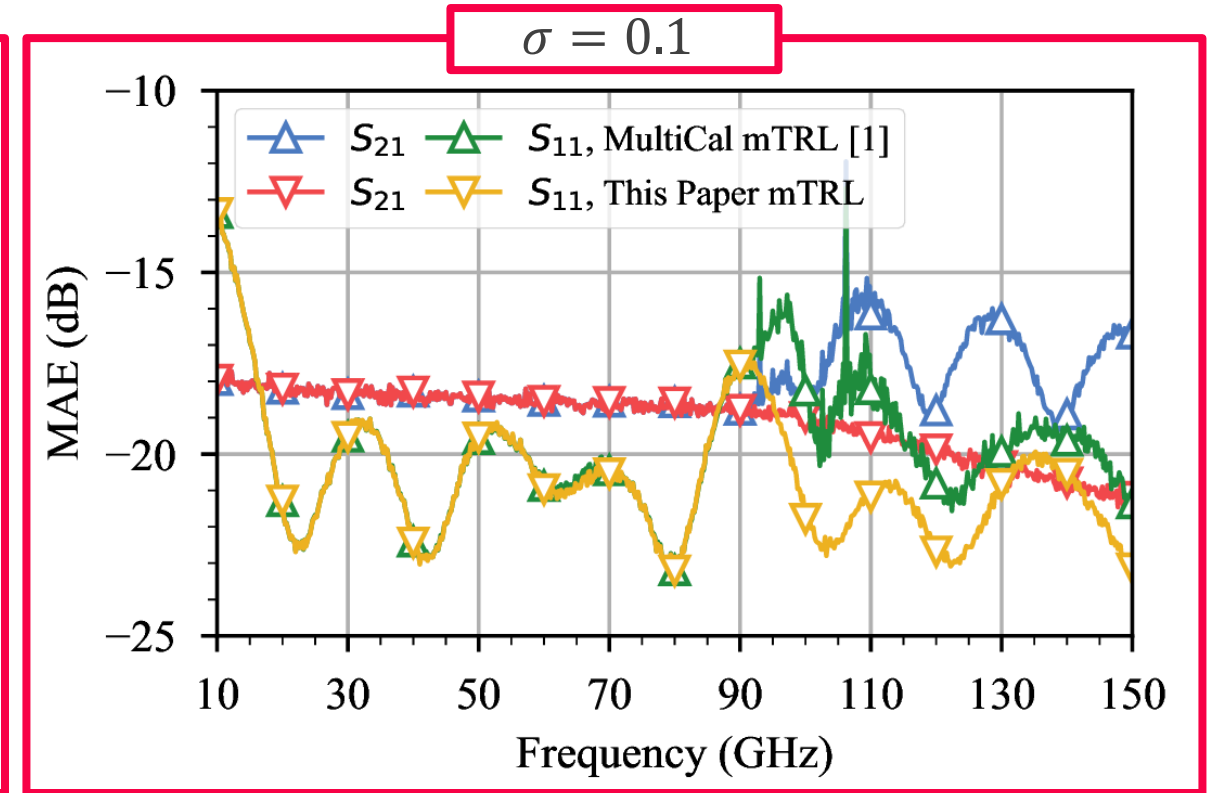
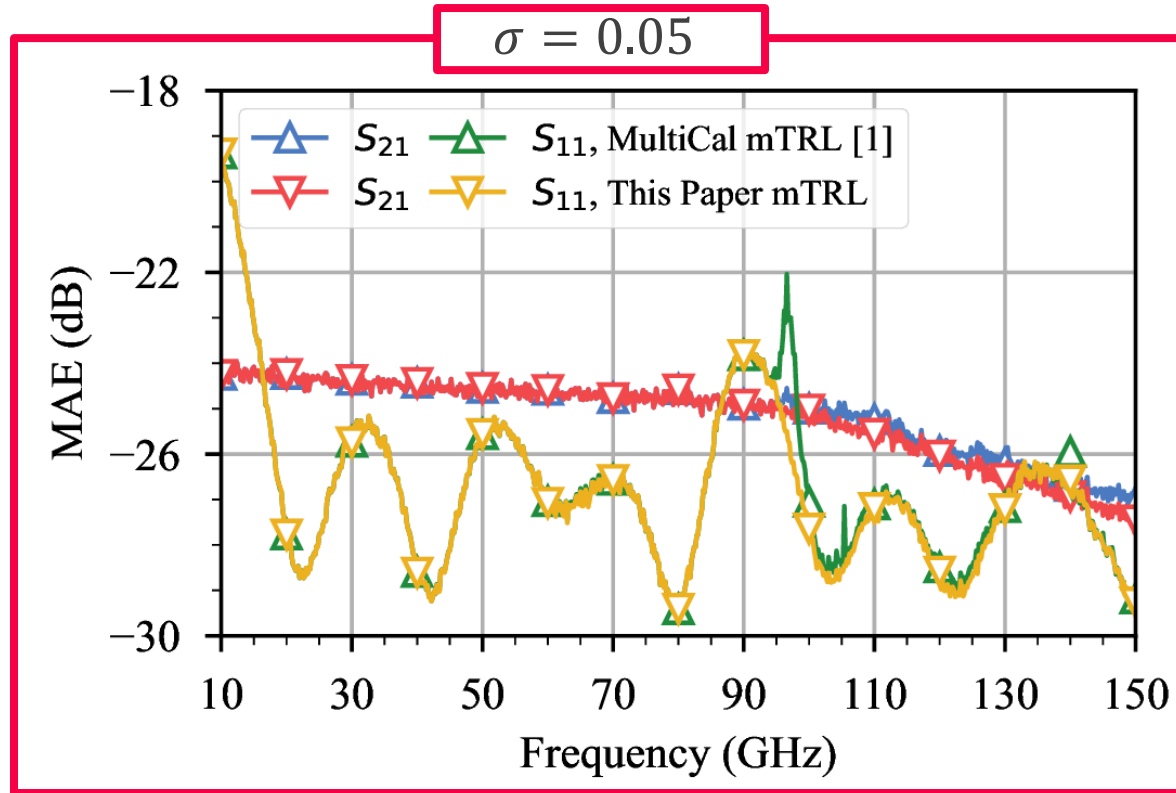


Calibrated short



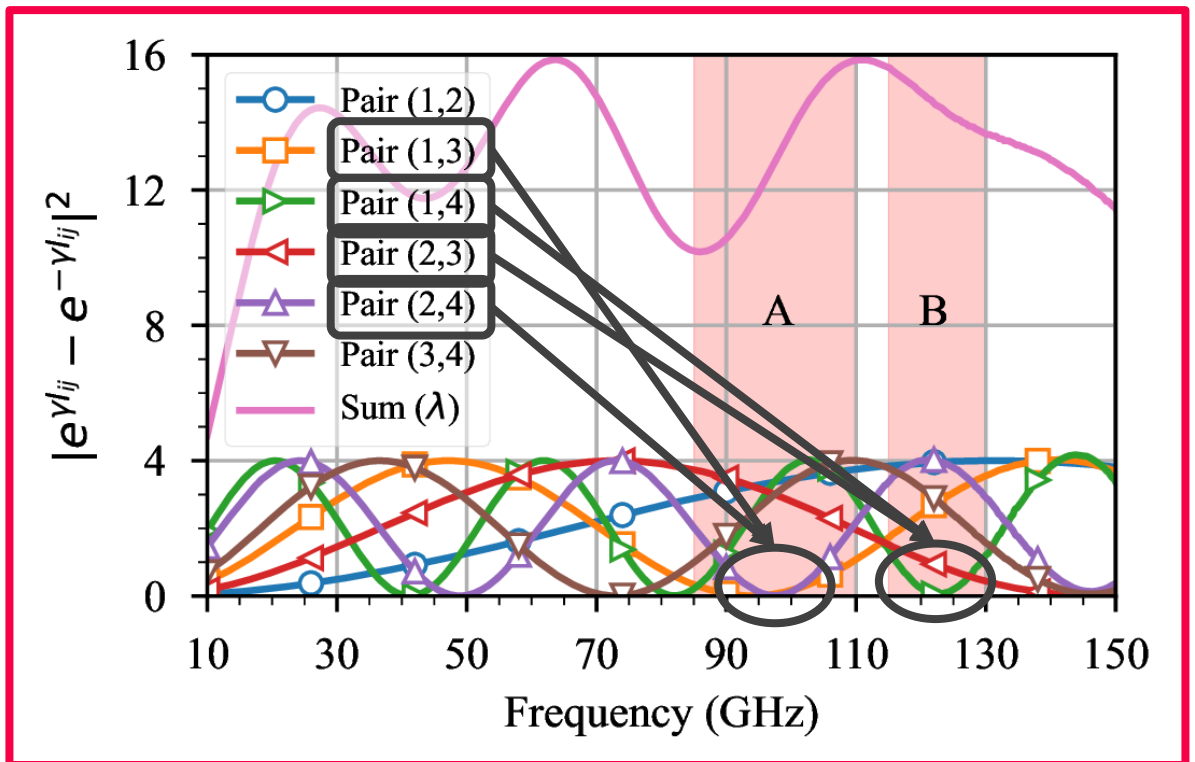
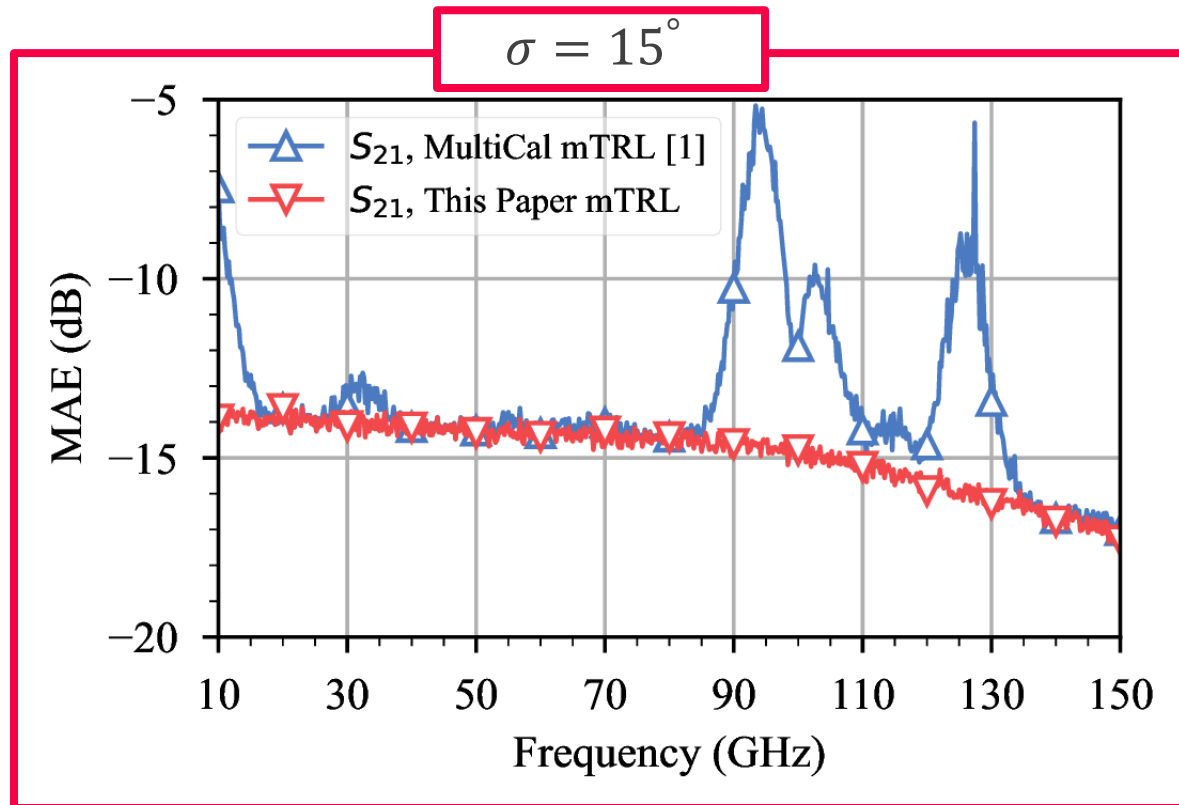
# Monte Carlo Experiment – Additive Noise

- Add noise to the measurements of the standards:  $S_{ij}^{New} = S_{ij}^{Meas} + Noise$
- Perform mTRL using distorted measurements at each trial ( $M = 2000$  trials).
- Calibrate a DUT and compute its **Mean-Absolute-Error**:  $MAE(S_{ij}) = \frac{1}{M} \sum_{m=1}^M |S_{ij,m}^{MC} - S_{ij}|$



# Monte Carlo Experiment – Phase Sensitivity

- Distort the phase of the measurements of the standards:  $\arg(S_{ij})^{New} = \arg(S_{ij})^{Meas} + Noise$
- Perform mTRL using distorted measurements at each trial ( $M = 2000$  trials).
- Calibrate a DUT and compute its **Mean-Absolute-Error**:  $MAE(S_{ij}) = \frac{1}{M} \sum_{m=1}^M |S_{ij,m}^{MC} - S_{ij}|$



# Summery

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- VNA error-box model can be simplified with the help of Kronecker product and matrix vectorization.
- Combining all line measurement with a self-derived weighting matrix.
- No matrix inverse. No covariance matrices.
- Solving a single eigenvalue problem.
- Better statistical performance.
- **Scalability**. For example, if you have **1000 Lines**, you will still solve a single  $4 \times 4$  eigenvalue problem. Imagine if you do that the old way!!



<https://github.com/ZiadHatab/multiline-trl-calibration>



Check my github repository and try the algorithm yourself.  
Feedbacks are very, very welcomed!!!

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